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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In the Application of: **Hiroyuki OHTA**

Group Art Unit: **2812**

Serial No.: **10/668,211**

Examiner: **Walter L. Lindsay, Jr.**

Filed: **September 24, 2003**

Confirmation No.: **1590**

For: **REDUCTION IN SOURCE-DRAIN RESISTANCE OF
SEMICONDUCTOR DEVICE**

Attorney Docket Number: **031106**

Customer Number: **38834**

INFORMATION DISCLOSURE STATEMENT
PURSUANT TO 37 C.F.R. §1.97(b)

Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

Date: January 28, 2005

Sir:

In compliance with 37 C.F.R. §1.56, Applicants direct the attention of the Patent and Trademark Office to the references listed on the attached PTO-1449. This paper is being filed within the time periods set forth in 37 C.F.R. §1.97(b).

Each item of information contained in this Information Disclosure Statement was first cited in a communication from a foreign patent office in a counter part foreign application not more than three months prior to the filing of this statement.

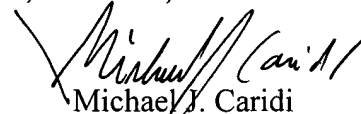
A copy of each non-U.S. document is enclosed herewith.

Information Disclosure Statement
Application No.: 10/668,211
Attorney Docket No. 031106

If there are any fees due in connection with the filing of this paper, please charge Deposit
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Respectfully submitted,

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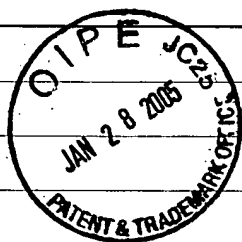
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Enclosure: PTO Form 1449 and Reference(s)

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| | Applicant(s): Hiroyuki OHTA et al. | |
| | Filing Date: September 24, 2003 | Group Art Unit: 2812 |

U.S. PATENT DOCUMENTS

| Examiner Initial | Document No. | Name | Date | Class | Subclass | Filing Date (If appropriate) |
|---------------------|--------------|------|------|-------|----------|---------------------------------|
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FOREIGN PATENT DOCUMENTS

| Examiner Initial | Document No. | Date | Country | Translation (Yes or No) |
|---------------------|--------------|-----------|---------|----------------------------|
| | 07-066406 | 3/10/1995 | JAPAN | Abstract |
| | 05-218410 | 8/27/1993 | JAPAN | Abstract |
| | 2002-151683 | 5/24/2002 | JAPAN | Abstract |
| | 2001-274385 | 10/5/2001 | JAPAN | Abstract |
| | 05-029341 | 2/5/1993 | JAPAN | Abstract |
| | | | | |

OTHER DOCUMENTS

| | | |
|----------|--|---|
| | | Japanese Office Action (With Translation) – Mailing date 11/9/2004 – Patent Application No. 2002-285372 |
| Examiner | | Date Considered |